

Product Change Notification: BLAS-24KM0I079

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25-Nov-2024

Product Category:

USB Power Delivery

Notification Subject:

CCB 7286 Initial Notice: Qualification of ATP7 as an additional assembly site for MCP22350-1I/Q8X, MCP22350-2I/Q8X, MCP22350T-1I/Q8X, MCP22350T-2I/Q8X, UPD350A/Q8X, UPD350A-I/Q8X, UPD350B-I/Q8X, UPD350B-I/Q8X, UPD350B-I/Q8X, UPD350D-I/Q8X, UPD350D-I/Q8X, UPD350DT/Q8X and UPD350DT-I/Q8X catalog part numbers (CPN) available in 28L VQFN (4x4x0.9mm) package.

Affected CPNs:

BLAS-24KMOI079_Affected_CPN_11252024.pdf BLAS-24KMOI079 Affected CPN 11252024.csv

PCN Status: Initial Notification

PCN Type: Manufacturing Change

Microchip Parts Affected: Please open one of the files found in the Affected CPNs section. Note: For your convenience Microchip includes identical files in two formats (.pdf and .xls)

Description of Change: Qualification of ATP7 as an additional assembly site for MCP22350-1I/Q8X, MCP22350-2I/Q8X, MCP22350T-2I/Q8X, UPD350A/Q8X, UPD350A-I/Q8X, UPD350B-I/Q8X, UPD350B-I/Q8X, UPD350B-I/Q8X, UPD350D-I/Q8X, UPD350D-I/Q8X, UPD350DT/Q8X and UPD350DT-I/Q8X catalog part numbers (CPN) available in 28L VQFN (4x4x0.9mm) package.

Pre and Post Summary Changes:

| | Pre Change | Post Change |
|--|------------|-------------|
| | | |

| Assembly Site | Amkor Assembly & Test (Shanghai) Co., LTD (ANAC) | Amkor Assembly & Test (Shanghai) Co., LTD (ANAC) | Amkor Technology Philippines (P3/P4), INC. (ATP7) | | | | |
|---------------------------|---|---|---|--|--|--|--|
| Wire Material | CuPdAu | CuPdAu | CuPdAu | | | | |
| Die Attach Material | CRM-1085A | CRM-1085A | CRM-1085A | | | | |
| Molding Compound Material | G631BQF | G631BQF | G631BQF | | | | |
| Lead-Frame Material | C194 | C194 | C194 | | | | |

Impacts to Datasheet: None

Change Impact: None

Reason for Change: To improve on-time delivery performance by qualifying ATP7 as an additional

assembly site.

Change Implementation Status: In Progress

Estimated Qualification Completion Date: March 2025

Note: Please be advised the qualification completion times may be extended because of unforeseen business conditions however implementation will not occur until after qualification has completed and a final PCN has been issued. The final PCN will include the qualification report and estimated first ship date. Also note that after the estimated first ship date guided in the final PCN customers may receive pre and post change parts.

Timetable Summary:

| | November 2024 | | | | | > | March 2025 | | | | | |
|------------------------|---------------|----|----|----|----|---|------------|----|----|----|----|--|
| Work Week | 44 | 45 | 46 | 47 | 48 | | 09 | 10 | 11 | 12 | 14 | |
| Initial PCN Issue Date | | | | | Х | | | | | | | |

| Qual Report Availability | | | | | | Х |
|--------------------------|--|--|--|--|--|---|
| Final PCN Issue Date | | | | | | Х |

Method to Identify Change: Traceability Code

Qualification Plan: Please open the attachments included with this PCN labeled as PCN_#_Qual_Plan.

Revision History: November 27, 2024: Issued initial notification.

Note: The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable product.

Attachments:

PCN_BLAS-24KMOI079 Qual Plan.pdf

Please contact your local **Microchip sales office** with questions or concerns regarding this notification.

Terms and Conditions:

If you wish to <u>receive Microchip PCNs via email</u> please register for our PCN email service at our **PCN home page** select register then fill in the required fields. You will find instructions about registering for Microchips PCN email service in the **PCN FAQ** section.

If you wish to <u>change your PCN profile</u>, <u>including opt out</u>, please go to the **PCN home page** select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.

BLAS-24KMOI079 - CCB 7286 Initial Notice: Qualification of ATP7 as an additional assembly site for MCP22350-1I/Q8X, MCP22350-2I/Q8X, MCP22350T-2I/Q8X, UPD350A/Q8X, UPD350A-I/Q8X, UPD350B-I/Q8X, UPD350B-I/Q8X, UPD350B-I/Q8X, UPD350D-I/Q8X, UPD350D-I/Q8X, UPD350D-I/Q8X, UPD350D-I/Q8X, UPD350D-I/Q8X, UPD350DT-I/Q8X and UPD350DT-I/Q8X catalog part numbers (CPN) available in 28L VQFN (4x4x0.9mm) package.

Affected Catalog Part Numbers (CPN)

MCP22350-1I/Q8X

MCP22350-2I/Q8X

MCP22350T-1I/Q8X

MCP22350T-2I/Q8X

UPD350A/Q8X

UPD350A-I/Q8X

UPD350B/Q8X

UPD350B-I/Q8X

UPD350BT/Q8X

UPD350C/Q8X

UPD350C-I/Q8X

UPD350D/Q8X

UPD350D-I/Q8X

UPD350DT/Q8X

UPD350DT-I/Q8X

Date: Sunday, November 24, 2024



QUALIFICATION PLAN SUMMARY

PCN #: BLAS-24KMOI079

Date: November 21, 2024

Qualification of ATP7 as an additional assembly site for MCP22350-1I/Q8X, MCP22350-2I/Q8X, MCP22350T-1I/Q8X, MCP22350T-2I/Q8X, UPD350A/Q8X, UPD350A-I/Q8X, UPD350B/Q8X, UPD350B-I/Q8X, UPD350BT/Q8X, UPD350C/Q8X, UPD350C-I/Q8X, UPD350D/Q8X, UPD350DT-I/Q8X, UPD350DT-I/Q8X catalog part numbers (CPN) available in 28L VQFN (4x4x0.9mm) package.

Purpose:

Qualification of ATP7 as an additional assembly site for MCP22350-1I/Q8X, MCP22350-2I/Q8X, MCP22350T-1I/Q8X, MCP22350T-2I/Q8X, UPD350A/Q8X, UPD350A-I/Q8X, UPD350B/Q8X, UPD350B-I/Q8X, UPD350BT/Q8X, UPD350C-I/Q8X, UPD350D-I/Q8X, UPD350D-I/Q8X, UPD350DT/Q8X and UPD350DT-I/Q8X catalog part numbers (CPN) available in 28L VQFN (4x4x0.9mm) package.

CCB #: 7286

| | Assembly site | ATP7 | | | | |
|---------------------|--|---------------|--|--|--|--|
| | BD Number | BD-002810-01 | | | | |
| | MP Code (MPC) | TAT027Q8XA0A | | | | |
| Micc | Part Number (CPN) | UPD350A-I/Q8X | | | | |
| Misc. | MSL information | MSL3, 260'C | | | | |
| | Assembly Shipping Media (T/R, Tube/Tray) | Tray | | | | |
| | Base Quantity Multiple (BQM) | 490 | | | | |
| | Reliability Site | MTAI | | | | |
| | Paddle size | 114x114mils | | | | |
| | Material | C194 | | | | |
| | DAP Surface Prep | DR-Ag | | | | |
| | Treatment | Roughened | | | | |
| <u>Lead-Frame</u> | Process | Etched | | | | |
| <u>Leau-Frairie</u> | Lead-lock | Yes | | | | |
| | Part Number | 101369406 | | | | |
| | Lead Plating | Matte Sn | | | | |
| | Strip Size | 250x70mm | | | | |
| | Strip Density | 676 | | | | |
| Bond Wire | Material | CuPdAu | | | | |
| Die Attach | Part Number | CRM-1085A | | | | |
| <u>Die Attacii</u> | Conductive | Yes | | | | |
| <u>MC</u> | Part Number | G631BQF | | | | |
| | Package Type | VQFN | | | | |
| <u>PKG</u> | Pin/Ball Count | 28 | | | | |
| | PKG width/size | 4x4x0.9mm | | | | |

| Test Name | Conditions | Sample Size | Min. Qty of Spares per Lot | Qty of 7 | Total | Fail Accept | Est. Dur. | . ATE | REL | Pkg. | Special Instructions |
|------------------------------------|---|---------------------------------|-----------------------------|----------|-------|------------------|-----------|-----------|-------|-------|---|
| | | · | (should be properly marked) | | | Qty | | Test Site | | | · |
| Standard Pb-free | J-STD-002D ; Perform 8 hour steam aging for Matte tin finish and 1 hour steam aging for NiPdAu finish prior to | 22 | 5 | 1 | 27 | > 95% lead | 5 | MTAI | MTAI | VOEN | |
| Solderability | testing. | 22 | | ' | 21 | coverage | 3 | WITAI | WITAI | VQIIV | |
| | | | | | | | | | | | |
| | Standard Pb-free: Matte tin/ NiPdAu finish, SAC solder, wetting temp 245°C for both SMD & through hole packages. | | | | | | | | | | Standard Pb-free solderability is the requirement. |
| Backward Solderability | J-STD-002D ;Perform 8 hours steam aging for Matte tin finish and 1 hour steam aging for NiPdAu finish prior to | 22 | 5 | 1 | 27 | > 95% lead | 5 | MTAI | MTAI | VQFN | SnPb solderability (backward solderability- SMD reflow soldering) is required for any plating |
| | testing. | | | | | coverage | | | | | related changes and highly recommended for other package BOM changes. |
| | Backward: Matte tin/ NiPdAu finish, SnPb solder, wetting temp 215°C for SMD. | | | | | | | | | | |
| Wire Bond Pull - WBP | Mil. Std. 883-2011 | 5 | 0 | 1 | 5 | 0 fails after TC | 5 | ATP7 | ATP7 | VQFN | 30 bonds from a min. 5 devices. |
| Wire Bond Shear - WBS | CDF-AEC-Q100-001 | 5 | 0 | 1 | 5 | | 5 | ATP7 | ATP7 | VQFN | 30 bonds from a min. 5 devices. |
| Wire Sweep | | | | | | | | ATP7 | ATP7 | VQFN | Required for any reduction in wire bond thickness. |
| Physical Dimmensions | Measure per JESD22 B100 and B108 | 10 | 0 | 3 | 30 | | 5 | ATP7 | ATP7 | | |
| External Visual | Mil. Std. 883-2009/2010 | All devices prior to submission | 0 | 3 | ΔΙΙ | 0 | 5 | MTAI | MTAI | VOEN | |
| External visual | 1VIII. Gtd. 000-2003/2010 | for qualification testing | | | | | J | WITAI | | | |
| HTSL (High Temp | JESD22-A103. +175 C for 504 hours or 150°C for 1008 hrs. | 45 | 5 | 1 | 50 | 0 | 10 | MTAI | MTAI | VQFN | |
| Storage Life) | Electrical test pre and post stress at +25°C and +85°C hot temp. | | | | | | | | | | |
| | | | | | | | | | | | |
| Preconditioning - | JESD22-A113. +150°C Bake for 24 hours, moisture loading requirements per MSL level + 3X reflow at peak reflow | 231 | 15 | 3 | 738 | 0 | 15 | MTAI | MTAI | | Spares should be properly identified. |
| Required for surface mount devices | temperature per Jedec-STD-020E for package type; Electrical test pre and post stress at +25°C. | | | | | | | | | | 77 parts from each lot to be used for HAST, uHAST, Temp Cycle test. |
| | MSL3, 260°C | | | | | | | | | | |
| | | | | | | | | | | | |
| | | | | | | | | | | | |
| HAST | JESD22-A110. +130°C/85% RH for 96 hours or 110°C/85%RH for 264 hours. | 77 | 5 | 3 | 246 | 0 | 10 | MTAI | MTAI | | Spares should be properly identified. |
| | Electrical test pre and post stress at +25°C and +85°C hot temp. | | | | | | | | | | Use the parts which have gone through Pre-conditioning. |
| | Libertical test pre una pest stress at 120 0 and 100 0 not temp. | | | | | | | | | | |
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| | | | | | | | | | | | |
| UHAST | JESD22-A118. +130°C/85% RH for 96 hrs or +110°C/85% RH for 264 hrs. | 77 | 5 | 3 | 246 | 0 | 10 | MTAI | MTAI | | Spares should be properly identified. Use the parts which have gone through Pre-conditioning. |
| | Electrical test pre and post stress at +25°C | | | | | | | | | | ose the parts which have gone through Pre-conditioning. |
| | | | _ | | | | | <u> </u> | | | |
| Temp Cycle | JESD22-A10465°C to +150°C for 500 cycles. | 77 | 5 | 3 | 246 | 0 | 15 | MTAI | MTAI | | Spares should be properly identified. Use the parts which have gone through Pre-conditioning. |
| | Electrical test pre and post stress at +85°C hot temp; 3 gram force WBP, on 5 devices from 1 lot, test following Temp | | | | | | | | | | Too the parts which have gone through the containering. |
| | Cycle stress. | | | | | | | | | | |
| | | | | | | | | | | | |